

## **Lect. SEDAT CANLI**

### **Personal Information**

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### **International Researcher IDs**

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### **Education Information**

Postgraduate, Middle East Technical University, Graduate School of Natural and Applied Sciences, Mikro Ve Nanoteknoloji (YI) (Tezli), Turkey 2007 - 2010

Undergraduate, Middle East Technical University, Faculty of Arts and Sciences, Department of Physics, Turkey 1999 - 2006

### **Foreign Languages**

English, C2 Mastery

### **Dissertations**

Postgraduate, Thickness determination of thin films by energy dispersive x-ray spectroscopy, Middle East Technical University, Graduate School of Natural and Applied Sciences, Mikro Ve Nanoteknoloji (YI) (Tezli), 2010

### **Academic Titles / Tasks**

Lecturer, Middle East Technical University, Presidency Office, Presidency Office, 2010 - Continues

### **Patent**

CANLI S., A thickness determination method, Patent, CHAPTER G Physics, Standard Registration, 2012

### **Metrics**

Publication: 5

Citation (WoS): 23

Citation (Scopus): 16

H-Index (WoS): 3

H-Index (Scopus): 3